

Holt Integrated Circuits

23351 Madero Mission Viejo, CA 92691

PRODUCT CHANGE NOTIFICATION (PCN)

			PCN INFORM	MATION			
PCN#	0704		Date:		12/03/07	_	
Title	ARINC 429 Line Driver D Products	ARINC 429 Line Driver Die Change for HI-8585 & HI-8586 Products		Date Effective	ə:	12/03/07	
Contact:	Scott Paladichuk			Title:		Director of Quality	
Phone #:	949-859-8800						
Fax #:	949-859-9643			Attachment:		Yes	
E-mail:	spaladichuk@holtic.com			Samples:		Available	
		MEANS	OF DISTINGUISHING	G CHANGED		ICES	
	Product Mark		Back Mark		\boxtimes	Date Code	Other
Please see	e attachment for Date Codes						
			CHANGE 1	ГҮРЕ			
	Design		Electrical Specification			Mechanical Specification	
	Wafer Fab Site		Wafer Fab Material			Wafer Fab Process	
	Assembly Site		Assembly Material			Assembly Process	
	Test Site		Test Process			Packing/Shipping/Labeling	
	Other:						
			DETAIL	c			
REASON I 1. Repla susce 2. To tig 3. To all PRODUCT HI-8585 & RELIABLI	FION OF CHANGE: ge from HI8590 to HI8595 for a FOR CHANGE: ace the zener diode-based vo eptible to drift or variation du ghtly reference the ARINC 429 ow the use of industry best- AFFECTED: HI-8586, all package options TY/QUALIFICATION SUMMAR e attachment for reliability da	Itage refer ring expos 9 NULL vol practice Ni	ence cells with highly st sure to temperature extre tage to the chip GND.	emes encounter			
riease see	e attachment for renability da					2011	
			ner Acknowledgeme				
approval	rds indicate that you requi or request additional infor I that this change is accep	mation. If					
early vers	rves the right to ship eithe sion has been depleted.	r version	manufactured after th	e process cha	nge e	ffective date until the inve	entory on the
Customer	Signature/Date						
						Approval for shipments price	or to effective date
HOLT ACK	KNOWLEDGEMENT OF RECE	IPT:					
RECEIVEL	O BY:						



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ATTACHMENT I INFORMATION – PCN 0704

PCN Type: Design Change

Title ARINC 429 Line Driver Die Change for HI-8585 & HI-8586

Data Sheet

Change: No

Detail of Change

The new design has been characterized against all requirements of the ARINC 429 specification and the Holt HI-8585 & HI-8586 Data Sheets. No changes are necessary to the data sheet to accommodate the new die. This change is

therefore considered a Form, Fit and Function replacement for the existing Holt products.

Please see Table 2 as shown below for when die change was implemented by date code

Detail of Reliability Table 1

Qualification results for the HI8595 die from Lot 3788, Date Code 0643 are as follow:

Stress/Test	Test Condition (Temp/Bias)	SS/Accept #	Result P/F
High Temperature Operating Life	Static Operating Condition, Vcc Max = 15.0V, 125°C, 1000 Hrs	45/0	Р
High Temperature Storage Life	150°C, 1000 Hrs.	45/0	Р
High Accelerated Saturation Test (HAST)*	130 °C 85%RH 2atm, Biased 96 Hrs.	45/0	Р
Temperature Cycle*	-65°C to +150 °C, 1000 cycles	45/0	Р
Pressure Pot*	121 °C 100%RH 2atm, 96 Hrs.	45/0	Р
Latch-up	Holt Specification	9/0	Р
Electrostatic Discharge Human Body Model (ESD_HBM)	+/- 4000 V MIL-STD-883, Method 3015	10/0	Р
Noted samples (*) were subjected to precond	ditioning prior to start of stress test.	•	

Detail of Date Code Implementation

Table 2

Tuble 2							
Affected Parts	Date Code	Affected Parts	Date Code				
HI-8585PSI	0728	HI-8586PSI	0640				
HI-8585PSIF	0730	HI-8586PSIF	0730				
HI-8585PST	0730	HI-8586PST	0730				
HI-8585PSTF	0730	HI-8586PSTF	0730				
HI-8585PSM	0730	HI-8586PSM	0730				
HI-8585PSMF	0730	HI-8586PSMF	0730				
HI-8585PDI	0730	HI-8586PDI	0730				
HI-8585PDIF	0730	HI-8586PDIF	0730				
HI-8585PDT	0730	HI-8586PDT	0730				
HI-8585PDTF	0730	HI-8586PDTF	0730				
HI-8585PDM	0730	HI-8586PDM	0730				
HI-8585PDMF	0730	HI-8586PDMF	0730				
HI-8585CRI	0801	HI-8586CRI	0801				
HI-8585CRT	0801	HI-8586CRT	0801				
HI-8585CRM	0801	HI-8586CRM	0801				